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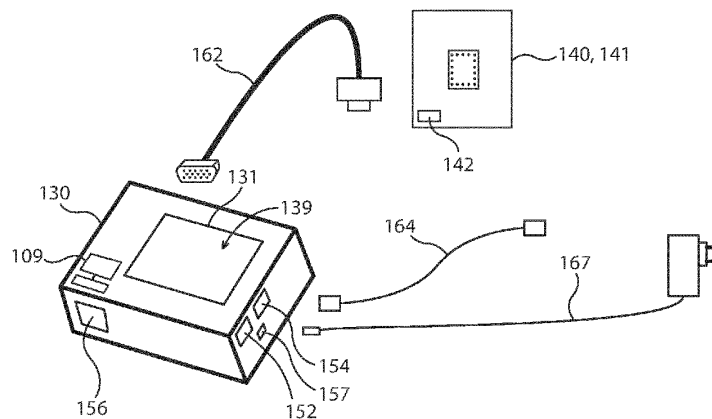
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(54) Title: AUTOMATED TEST EQUIPMENT FOR TESTING SEMICONDUCTOR DEVICES

Fig. 1A



(57) Abstract: An automated test equipment (ATE) for testing semiconductor devices, the test equipment comprises a test handler, a spare part, or a contactor socket, and a semiconductor devices tester. The spare part comprises an electronic component for storing and/or processing data regarding the spare part or a portion thereof. The test equipment comprises an operator terminal comprising a display or GUI and a data exchange interface which is connected or connectable to the electronic component within the spare part, for at least displaying data stored therein. The ATE further comprises a data buffer unit for buffering the data, a maintenance planning and control unit for planning and controlling maintenance actions of the test equipment, and a dedicated database residing in a control computer.

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